

# **VL405 Design for Testability**

Lab Assignment 2

## **Design and Fault Analysis of Even Parity Generator and Checker Circuits using VHDL**

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## 1 Objective

The objective of this experiment is to design and implement even parity generator and checker circuits using VHDL, and to analyze their behavior under stuck-at fault conditions (SA0 and SA1). The experiment aims to verify the correctness of the parity-based error detection mechanism, study the limitations of fault detection, and understand the practical applications of parity codes in digital system reliability.

For this lab, we will assume that there are no stuck-at faults at the inputs of any gate.

## 2 Theory

### 2.1 Stuck-At Fault Model

The stuck-at fault model is the most widely used fault model in digital testing. It represents a logical failure in which a signal line (input, output, or internal net) of a circuit is assumed to be permanently fixed at a logic level, irrespective of the actual inputs applied to the circuit. Such faults generally occur due to manufacturing defects like short-circuits, open-circuits, or wear-out effects in integrated circuits.

- **Stuck-at-0 (SA0):** The line is permanently tied to logic '0'.
- **Stuck-at-1 (SA1):** The line is permanently tied to logic '1'.

This abstraction does not refer to a physical short to ground or VDD but instead to the logical behavior of the faulty circuit. For instance, if a line is modeled as SA0, then whenever the circuit attempts to drive that line to '1', the actual response will still be '0', leading to a logic error.

The stuck-at fault model is preferred because:

1. It simplifies fault analysis while still covering a wide range of practical defects.
2. Tests designed for single stuck-at faults often detect multiple other fault types.
3. It allows systematic test generation using Automatic Test Pattern Generation (ATPG).

### 2.2 Test Pattern Generation

To detect a stuck-at fault, we must apply test vectors that **differentiate the fault-free circuit from the faulty circuit**. The general strategy is:

- **SA0 detection:** Apply an input combination that would force the fault-free output to be '1'. If the output remains '0', the fault is detected.
- **SA1 detection:** Apply an input combination that would force the fault-free output to be '0'. If the output remains '1', the fault is detected.

Thus, an effective test set is one where every node in the circuit is sensitized to both '0' and '1' conditions at least once, ensuring that both SA0 and SA1 faults are observable at the primary outputs.

## 2.3 Gate-Specific Fault Detection Requirements

### 2.3.1 3-Input Even Parity Generator

A 3-input even parity generator outputs a parity bit such that the total number of '1's in the inputs plus the parity bit is **even**. The function can be expressed as:

$$P = A \oplus B \oplus C$$

where  $A, B, C$  are inputs and  $P$  is the parity bit.

- **SA0 at Output (P/0):** To detect this, inputs must be applied such that the correct parity output is '1'. If the output remains stuck at '0', the fault is detected. Example test vectors: 001, 010, 100, 111.
- **SA1 at Output (P/1):** To detect this, inputs must be applied such that the correct parity output is '0'. If the output remains stuck at '1', the fault is detected. Example test vectors: 000, 011, 101, 110.

Table 1: Truth Table for 3-Bit Even Parity Generator

A	B	C	P
0	0	0	0
0	0	1	1
0	1	0	1
0	1	1	0
1	0	0	1
1	0	1	0
1	1	0	0
1	1	1	1

### 2.3.2 4-Bit Even Parity Checker

A 4-bit even parity checker verifies whether the received 4-bit word (3 data + 1 parity) contains an **even number of 1's**. Its output, Parity Error Check (PEC), is given by:

$$PEC = A \oplus B \oplus C \oplus P$$

where  $P$  is the transmitted parity bit.

- **SA0 at Output (PEC/0):** Apply inputs that should produce '1' (odd number of 1's). If PEC remains at '0', the fault is detected.
- **SA1 at Output (PEC/1):** Apply inputs that should produce '0' (even number of 1's). If PEC remains at '1', the fault is detected.

Table 2: Truth Table for 4-Bit Even Parity Checker

A	B	C	P	PEC
0	0	0	0	0
0	0	0	1	1
0	0	1	0	1
0	0	1	1	0
0	1	0	0	1
0	1	0	1	0
0	1	1	0	0
0	1	1	1	1
1	0	0	0	1
1	0	0	1	0
1	0	1	0	0
1	0	1	1	1
1	1	0	0	0
1	1	0	1	1
1	1	1	0	1
1	1	1	1	0

### 2.3.3 Verifying the truth table of a 4-bit Even parity checker circuit

The given design implements a 4-bit even parity checker with fault injection capability. A parity checker is a combinational circuit that determines whether the number of logic '1's in a set of inputs is even or odd. For four data inputs  $A$ ,  $B$ ,  $C$ , and  $D$ , the parity output  $P$  is computed using XOR operations:

$$P = (A \oplus B) \oplus (C \oplus D)$$

Here, two intermediate signals are defined:

$$\text{temp1} = A \oplus B, \quad \text{temp2} = C \oplus D$$

and the final parity is obtained as  $P = \text{temp1} \oplus \text{temp2}$ .

To study fault tolerance, the circuit introduces the **stuck-at fault model** through a 3-bit control input, **Ctrl(2:0)**. A stuck-at fault forces an internal node to remain permanently at logic '0' (SA0) or logic '1' (SA1), irrespective of the actual inputs. This allows simulation of common manufacturing defects or physical failures in digital hardware.

The control signal has the following functionality:

- **Ctrl(2)** = 0: Normal operation, no faults injected.
- **Ctrl(2)** = 1: Fault mode enabled.
  - **Ctrl(1)** = 0: Fault applied to **temp1** ( $A \oplus B$ ).
    - \* **Ctrl(0)** = 0: **temp1** stuck-at-0.
    - \* **Ctrl(0)** = 1: **temp1** stuck-at-1.
  - **Ctrl(1)** = 1: Fault applied to **temp2** ( $C \oplus D$ ).
    - \* **Ctrl(0)** = 0: **temp2** stuck-at-0.

\* Ctrl(0) = 1: temp2 stuck-at-1.

Thus, the design can be operated in five distinct modes:

1. Normal mode (Ctrl = 000)
2. temp1 stuck-at-0 (Ctrl = 100)
3. temp1 stuck-at-1 (Ctrl = 101)
4. temp2 stuck-at-0 (Ctrl = 110)
5. temp2 stuck-at-1 (Ctrl = 111)

This fault injection mechanism enables verification of the complete truth table of the parity checker under both fault-free and faulty conditions. By comparing the observed output  $P$  with the expected parity result for all input combinations, the behavior of the circuit under different fault scenarios can be thoroughly analyzed.

### 3 VHDL Implementation

#### 3.1 3-Input Even Parity Generator

##### 3.1.1 3-Input Even Parity Generator Entity and Architecture

```

1 library IEEE;
2 use IEEE.STD_LOGIC_1164.ALL;
3
4 entity three_bit_even_parity is
5 port(
6   A: in std_logic;
7   B: in std_logic;
8   C: in std_logic;
9   P: out std_logic
10 );
11 end entity three_bit_even_parity;
12
13 architecture Behavioral of three_bit_even_parity is
14   signal temp : std_logic;
15 begin
16   temp <= A xor B;
17   P <= temp xor C;
18 end Behavioral;

```

Listing 1: 3-Input Even Parity Generator Implementation

##### 3.1.2 3-Input Even Parity Generator Testbench

```

1 library IEEE;
2 use IEEE.STD_LOGIC_1164.ALL;
3
4 entity three_bit_even_parity_tb is
5 end three_bit_even_parity_tb;
6
7 architecture test of three_bit_even_parity_tb is
8   component three_bit_even_parity
9   port(
10    A: in std_logic;
11    B: in std_logic;
12    C: in std_logic;
13    P: out std_logic
14 );
15 end component three_bit_even_parity;
16
17 signal test_A: std_logic;
18 signal test_B: std_logic;
19 signal test_C: std_logic;
20 signal test_P: std_logic;
21
22 begin
23   UUT : three_bit_even_parity

```

```

24 port map(
25   A=>test_A,
26   B=> test_B,
27   C=> test_C,
28   P=>test_P
29 );
30
31 stimulus_process: process
32 begin
33   test_A <= '1';
34   test_B <= '1';
35   test_C <= '1';
36   wait for 10ns;
37
38   if test_P = '0' then
39     report "Stuck at 0 fault detected at odd function output!" severity error;
40   else
41     report "Odd function output is correct" severity note;
42   end if;
43
44   test_A <= '0';
45   test_B <= '0';
46   test_C <= '1';
47   wait for 10ns;
48
49   if test_P = '0' then
50     report "Stuck at 0 fault detected at odd function output!" severity error;
51   else
52     report "odd function output is correct" severity note;
53   end if;
54
55   test_A <= '1';
56   test_B <= '0';
57   test_C <= '1';
58   wait for 10ns;
59
60   if test_P = '1' then
61     report "Stuck at 1 fault detected at odd function output!" severity error;
62   else
63     report "odd function output is correct" severity note;
64   end if;
65
66   test_A <= '0';
67   test_B <= '1';
68   test_C <= '1';
69   wait for 10ns;
70
71   if test_P = '1' then
72     report "Stuck at 1 fault detected at odd function output!" severity error;
73   else
74     report "odd function output is correct" severity note;
75   end if;
76
77   test_A <= '1';
78   test_B <= '1';
79   test_C <= '0';
80   wait for 10ns;
81
82   if test_P = '1' then
83     report "Stuck at 1 fault detected at odd function output!" severity error;
84   else
85     report "Odd function output is correct" severity note;
86   end if;
87
88   test_A <= '0';
89   test_B <= '0';
90   test_C <= '0';
91   wait for 10ns;
92
93   if test_P = '1' then
94     report "Stuck at 1 fault detected at odd function output!" severity error;
95   else
96     report "odd function output is correct" severity note;
97   end if;
98
99   test_A <= '1';
100  test_B <= '0';
101  test_C <= '0';
102  wait for 10ns;
103
104  if test_P = '0' then
105    report "Stuck at 0 fault detected at odd function output!" severity error;
106  else
107    report "odd function output is correct" severity note;
108  end if;
109
110  test_A <= '0';
111  test_B <= '1';
112  test_C <= '0';
113  wait for 10ns;
114
115  if test_P = '0' then
116    report "Stuck at 0 fault detected at odd function output!" severity error;
117  else
118    report "odd function output is correct" severity note;
119  end if;
120
121  wait for 10ns;
122 end process stimulus_process;

```

```
123 end test;
```

Listing 2: 3-Input Even Parity Generator Testbench for Stuck-At Fault Detection

## 3.2 4-Input Even Parity Generator

### 3.2.1 4-Input Even Parity Generator Entity and Architecture

```

1  library IEEE;
2  use IEEE.STD_LOGIC_1164.ALL;
3
4
5  entity four_bit_even_parity_checker is
6  port(
7  A: in std_logic;
8  B: in std_logic;
9  C: in std_logic;
10 D: in std_logic;
11 P: out std_logic
12 );
13 end entity four_bit_even_parity_checker;
14
15 architecture Behavioral of four_bit_even_parity_checker is
16 signal temp1 : std_logic;
17 signal temp2 : std_logic;
18 begin
19 temp1 <= A xor B;
20 temp2 <= C xor D;
21 P <= temp1 xor temp2;
22 end Behavioral;
```

Listing 3: 3-Input Even Parity Generator Implementation

### 3.2.2 4-Input Even Parity Generator Testbench

```

1  library IEEE;
2  use IEEE.STD_LOGIC_1164.ALL;
3
4  entity four_bit_even_parity_checker_tb is
5  end four_bit_even_parity_checker_tb;
6
7  architecture test of four_bit_even_parity_checker_tb is
8  component four_bit_even_parity_checker
9  port(
10 A: in std_logic;
11 B: in std_logic;
12 C: in std_logic;
13 D: in std_logic;
14 P: out std_logic
15 );
16 end component four_bit_even_parity_checker;
17
18 signal test_A: std_logic;
19 signal test_B: std_logic;
20 signal test_C: std_logic;
21 signal test_D: std_logic;
22 signal test_P: std_logic;
23
24 begin
25 UUT : four_bit_even_parity_checker
26 port map(
27 A=>test_A,
28 B=> test_B,
29 C=> test_C,
30 D=> test_D,
31 P=> test_P
32 );
33
34 stimulus_process: process
35 begin
36 test_A <= '1';
37 test_B <= '1';
38 test_C <= '1';
39 test_D <= '1';
40 wait for 10ns;
41
42 if test_P = '1' then
43 report "Stuck at 1 fault detected at even parity output!" severity error;
44 else
45 report "Even parity output is correct" severity note;
46 end if;
47
48 test_A <= '1';
49 test_B <= '1';
50 test_C <= '0';
51 test_D <= '1';
```



```

52 wait for 10ns;
53
54 if test_P = '0' then
55     report "Stuck at 0 fault detected at even parity output!" severity error;
56 else
57     report "Even parity output is correct" severity note;
58 end if;
59
60 test_A <= '1';
61 test_B <= '1';
62 test_C <= '0';
63 test_D <= '0';
64 wait for 10ns;
65
66 if test_P = '1' then
67     report "Stuck at 1 fault detected at even parity output!" severity error;
68 else
69     report "Even parity output is correct" severity note;
70 end if;
71
72 test_A <= '1';
73 test_B <= '0';
74 test_C <= '0';
75 test_D <= '0';
76 wait for 10ns;
77
78 if test_P = '0' then
79     report "Stuck at 0 fault detected at even parity output!" severity error;
80 else
81     report "Even parity output is correct" severity note;
82 end if;
83
84 test_A <= '0';
85 test_B <= '0';
86 test_C <= '0';
87 test_D <= '0';
88 wait for 10ns;
89
90 if test_P = '1' then
91     report "Stuck at 1 fault detected at even parity output!" severity error;
92 else
93     report "Even parity output is correct" severity note;
94 end if;
95
96 wait for 10ns;
97 end process stimulus_process;
98 end test;

```

Listing 4: 4-Input Even Parity Generator Testbench for Stuck-At Fault Detection

### 3.3 Verifying the truth table of a 4-bit even parity checker circuit

#### 3.3.1 Verifying the truth table of a 4-bit even parity checker circuit Entity and Architecture

```

1  library IEEE;
2  use IEEE.STD_LOGIC_1164.ALL;
3
4  entity four_bit_parity_set is
5      Port (
6          A: in  std_logic;
7          B: in  std_logic;
8          C: in  std_logic;
9          D: in  std_logic;
10         P: out std_logic;
11         Ctrl: in  std_logic_vector(2 downto 0)
12     );
13 end four_bit_parity_set;
14
15 architecture Behavioral of four_bit_parity_set is
16     signal temp1 : std_logic;
17     signal temp2 : std_logic;
18 begin
19     process (A, B, C, D, Ctrl)
20     begin
21         if Ctrl(2) = '0' then
22             temp1 <= A xor B;
23             temp2 <= C xor D;
24             P <= temp1 xor temp2;
25         else
26             if Ctrl(1) = '0' then
27                 if Ctrl(0) = '0' then
28                     temp1 <= '0';
29                     temp2 <= C xor D;
30                     P <= temp1 xor temp2;
31                 else
32                     temp1 <= '1';
33                     temp2 <= C xor D;
34                     P <= temp1 xor temp2;
35                 end if;
36             else

```

```

37         if Ctrl(0) = '0' then
38             temp1 <= A xor B;
39             temp2 <= '0';
40             P <= temp1 xor temp2;
41         else
42             temp1 <= A xor B;
43             temp2 <= '1';
44             P <= temp1 xor temp2;
45         end if;
46     end if;
47 end if;
48 end process;
49 end Behavioral;

```

Listing 5: 3-Input Even Parity Generator Implementation

### 3.3.2 Verifying the truth table of a 4-bit even parity checker circuit Test-bench

```

1  library IEEE;
2  use IEEE.STD_LOGIC_1164.ALL;
3  use IEEE.NUMERIC_STD.ALL;
4
5  entity four_bit_parity_set_tb is
6  end four_bit_parity_set_tb;
7
8  architecture test of four_bit_parity_set_tb is
9  component four_bit_even_parity_checker
10     port(
11         A: in std_logic;
12         B: in std_logic;
13         C: in std_logic;
14         D: in std_logic;
15         P: out std_logic
16     );
17 end component four_bit_even_parity_checker;
18 type ctrl_array_t is array (natural range <>) of std_logic_vector(2 downto 0);
19 constant CTRL_VEC : ctrl_array_t := (
20     "000",
21     "100",
22     "101",
23     "110",
24     "111"
25 );
26
27 function expected_p (
28     a, b, c, d : std_logic;
29     ctrl : std_logic_vector(2 downto 0)
30 ) return std_logic is
31     variable t1_nom, t2_nom : std_logic;
32     variable t1_eff, t2_eff : std_logic;
33 begin
34     t1_nom := a xor b;
35     t2_nom := c xor d;
36
37     if ctrl(2) = '0' then
38         t1_eff := t1_nom;
39         t2_eff := t2_nom;
40     else
41         if ctrl(1) = '0' then
42             if ctrl(0) = '0' then
43                 t1_eff := '0';
44             else
45                 t1_eff := '1';
46             end if;
47             t2_eff := t2_nom;
48         else
49             t1_eff := t1_nom;
50             if ctrl(0) = '0' then
51                 t2_eff := '0';
52             else
53                 t2_eff := '1';
54             end if;
55         end if;
56     end if;
57     return t1_eff xor t2_eff;
58 end function;
59
60 function bstr(b : std_logic) return string is
61 begin
62     if b = '1' then return "1"; else return "0"; end if;
63 end function;
64
65 begin
66
67 uut : entity work.four_bit_parity_set
68     port map (
69         A => A,
70         B => B,
71         C => C,
72         D => D,

```

```

74         P    => P,
75         Ctrl => Ctrl
76     );
77
78     stim : process
79         constant STEP : time := 10 ns;
80         variable expP : std_logic;
81         variable vec  : std_logic_vector(3 downto 0);
82     begin
83         for j in CTRL_VEC'range loop
84             Ctrl <= CTRL_VEC(j);
85             wait for STEP;
86
87             for i in 0 to 15 loop
88                 vec := std_logic_vector(to_unsigned(i, 4));
89                 A <= vec(3);
90                 B <= vec(2);
91                 C <= vec(1);
92                 D <= vec(0);
93
94                 wait for STEP;
95
96                 expP := expected_p(A, B, C, D, Ctrl);
97
98                 assert P = expP
99                 report "Mismatch: Ctrl=" &
100                     bstr(Ctrl(2)) & bstr(Ctrl(1)) & bstr(Ctrl(0)) &
101                     " ABCD=" & bstr(A) & bstr(B) & bstr(C) & bstr(D) &
102                     " DUT_P=" & bstr(P) & " EXP_P=" & bstr(expP)
103                 severity error;
104             end loop;
105         end loop;
106
107         report "All parity and stuck-at tests completed successfully." severity note;
108         wait;
109     end process;
110 end architecture;

```

Listing 6: 4-Input Even Parity Generator Testbench for Stuck-At Fault Detection

## 4 Simulation Results

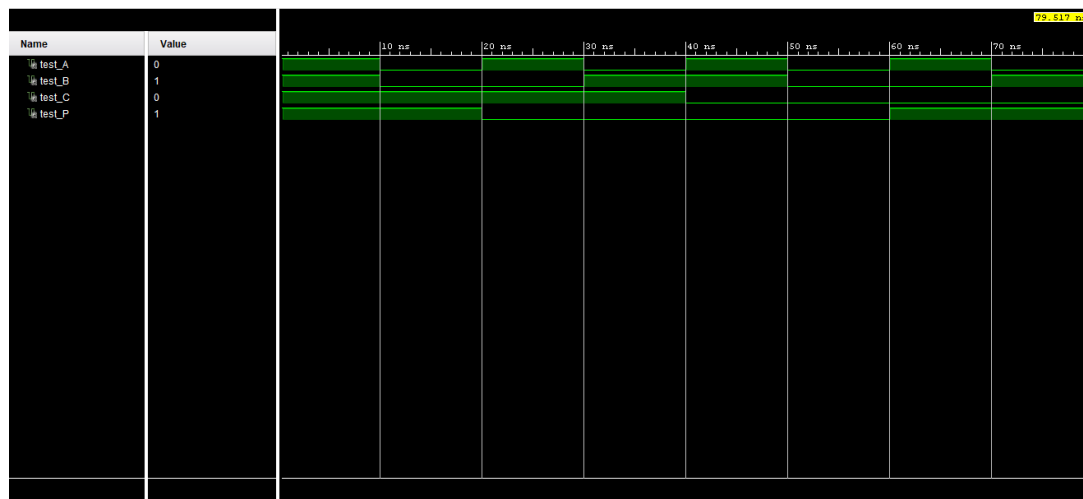


Figure 1: 3-Input Even Parity Generator Simulation Waveform for various inputs

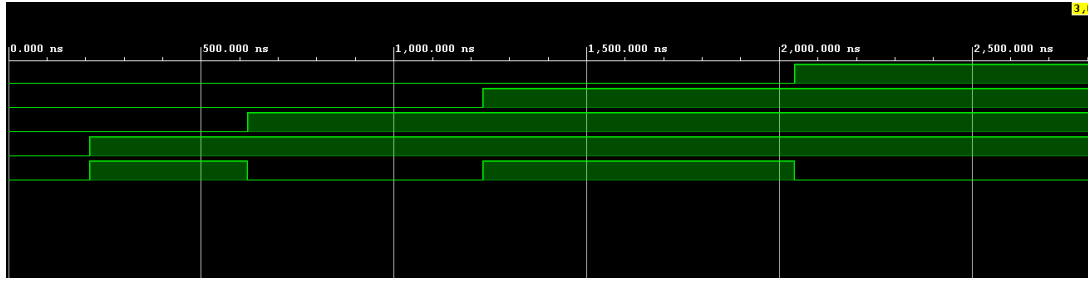


Figure 2: 4-Input Even Parity Generator Simulation Waveform for various inputs

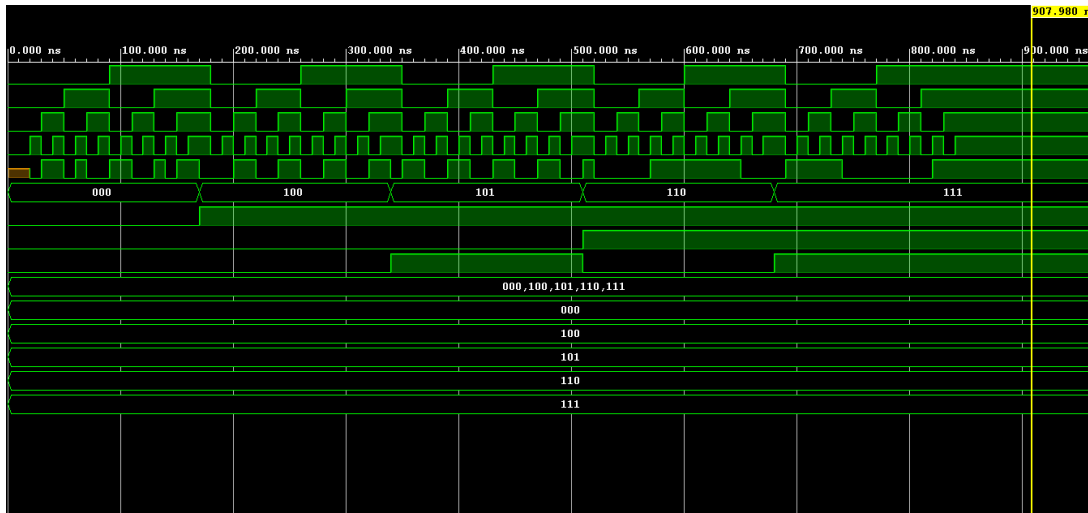


Figure 3: Verifying a 4-bit even parity checker

## 5 Conclusion

In this experiment, the design and verification of even parity generator and checker circuits were carried out using VHDL, with an emphasis on fault modeling through the stuck-at fault abstraction. Both 3-bit and 4-bit parity circuits were implemented, and their functional correctness was first established by exhaustively validating truth tables against simulation waveforms. The use of XOR-based logic confirmed the fundamental principle of parity coding—that the number of logical ‘1’s in a code word must remain even under correct transmission.

The second part of the study introduced single stuck-at faults (SA0 and SA1) on internal nodes of the 4-bit parity checker. By controlling the injection of faults using a dedicated **Ctrl** input, the circuit could be operated in five distinct modes, covering both fault-free and faulty conditions. Simulation results showed that faults introduced at intermediate nodes (**temp1** and **temp2**) directly impacted the final parity output, making them observable at the primary output. This confirmed the testability of the design and validated the sufficiency of the applied test patterns to sensitize all nodes.